OIPE OMUH-11618

MAR 2 5 2003

hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231

Ву: Д

Date: 3/17/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

M. Paumon

Applicant

: Udo Hartmann

Applic. No.

: 09/915,984

Filed

: July 25, 2001

Title

: Apparatus for Testing Semiconductor Devices

Examiner

: Paresh Patel

Group Art Unit: 2829

Hiar 27 2000 To 2800 Hall Ro

## AMENDMENT

Hon. Commissioner of Patents and Trademarks, Washington, D. C. 20231

## sir:

Responsive to the Office action dated December 16, 2002 kindly amend the above-identified application as follows:

## In the Claims:

Please cancel claims 1-8 and please add the following claims:

-- 9. A method for enabling semiconductor devices to be tested, the method which comprises:

D